PERFORMANCE CHECKSHEET

Model: AVR-EB4-B  
Type: Semiconductor Device Tester
S.N.: 13999
Date: July 29, 2020

Basic specifications: →

Test Waveforms

With an On Semi 1N4937 (date code 1832) installed in the AVX-TRR-MIX test jig, connected using the 60 cm / 24” coaxial cable:

I_F = +2A, I_R = -4A, I_RR = -1A.
100 Hz, 20 us PW.
5V (1A) / div, 40 ns/div.
Measured t_{RR} = 114 ns.

With a generic 1N4004 installed in the AVX-TRR-MIX test jig, connected using the 60 cm / 24” coaxial cable:

I_F = +2A, I_R = -4A, I_RR = -1A.
100 Hz, 20 us PW.
5V (1A) / div, 400 ns/div.
Measured t_{RR} = 944 ns.
Mainframe output, with a zero Ohm jumper installed in the AVX-TRR-MIX test jig:

50 V / div, 20 ns/div. +100V, -200V.

10% - 90% fall time shown.